

Search Notes



Application/Control No.

10/784,242

Examiner

Matthew Landau

Applicant(s)/Patent under Reexamination

OISHI ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	99, 100, 98, E33.075, E33.057, E33.056, E33.058, E33.059, E33.066, 79	5/22/06	me
362	294, 310		
372	36		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST Search (printout included)	5/22/06	me